

Notice of References Cited	Application/Control No. 10/714,207	Applicant(s)/Patent Under Reexamination CHIU ET AL.	
	Examiner Michael Trinh	Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,207,565	03-2001	Yeh et al.	438/669
	B	US-2003/0045098	03-2003	Verhaverbeke et al.	438/689
	C	US-5,298,112	03-1994	Hayasaka et al.	216/67
	D	US-2001/0038089	11-2001	Levenson et al.	252/79.1
	E	US-6,232,236	05-2001	Shan et al.	438/715
	F	US-5,411,631	05-1995	Hori et al.	216/72
	G	US-6,025,273	02-2000	Chen et al.	438/706
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.